



Welcome to [E-XFL.COM](https://www.e-xfl.com)

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, I ² C, LINbus, SCI, SPI
Peripherals	DMA, POR, PWM, WDT
Number of I/O	149
Program Memory Size	768KB (768K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 29x10b, 5x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	176-LQFP
Supplier Device Package	176-LQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/ppc5605bclu64

1 Introduction

1.1 Document overview

This document describes the features of the family and options available within the family members, and highlights important electrical and physical characteristics of the device.

1.2 Description

This family of 32-bit system-on-chip (SoC) microcontrollers is the latest achievement in integrated automotive application controllers. It belongs to an expanding family of automotive-focused products designed to address the next wave of body electronics applications within the vehicle.

The advanced and cost-efficient e200z0h host processor core of this automotive controller family complies with the Power Architecture technology and only implements the VLE (variable-length encoding) APU (Auxiliary Processor Unit), providing improved code density. It operates at speeds of up to 64 MHz and offers high performance processing optimized for low power consumption. It capitalizes on the available development infrastructure of current Power Architecture devices and is supported with software drivers, operating systems and configuration code to assist with users implementations.

Table 1. MPC5607B family comparison¹

Feature	MPC5605B			MPC5606B		MPC5607B
CPU	e200z0h					
Execution speed ²	Up to 64 MHz					
Code flash memory	768 KB			1 MB		1.5 MB
Data flash memory	64 (4 × 16) KB					
SRAM	64 KB			80 KB		96 KB
MPU	8-entry					
eDMA	16 ch					
10-bit ADC	Yes					
dedicated ³	7 ch	15 ch	29 ch	15 ch	29 ch	
shared with 12-bit ADC	19 ch					
12-bit ADC	Yes					
dedicated ⁴	5 ch					
shared with 10-bit ADC	19 ch					
Total timer I/O ⁵ eMIOS	37 ch, 16-bit	64 ch, 16-bit				
Counter / OPWM / ICOC ⁶	10 ch					
O(I)PWM / OPWFMB / OPWMCB / ICOC ⁷	7 ch					
O(I)PWM / ICOC ⁸	7 ch	14 ch				
OPWM / ICOC ⁹	13 ch	33 ch				
SCI (LINFlex)	4	8	10	8	10	
SPI (DSPI)	3	5	6	5	6	

2 Block diagram

Figure 1 shows a top-level block diagram of the MPC5607B.

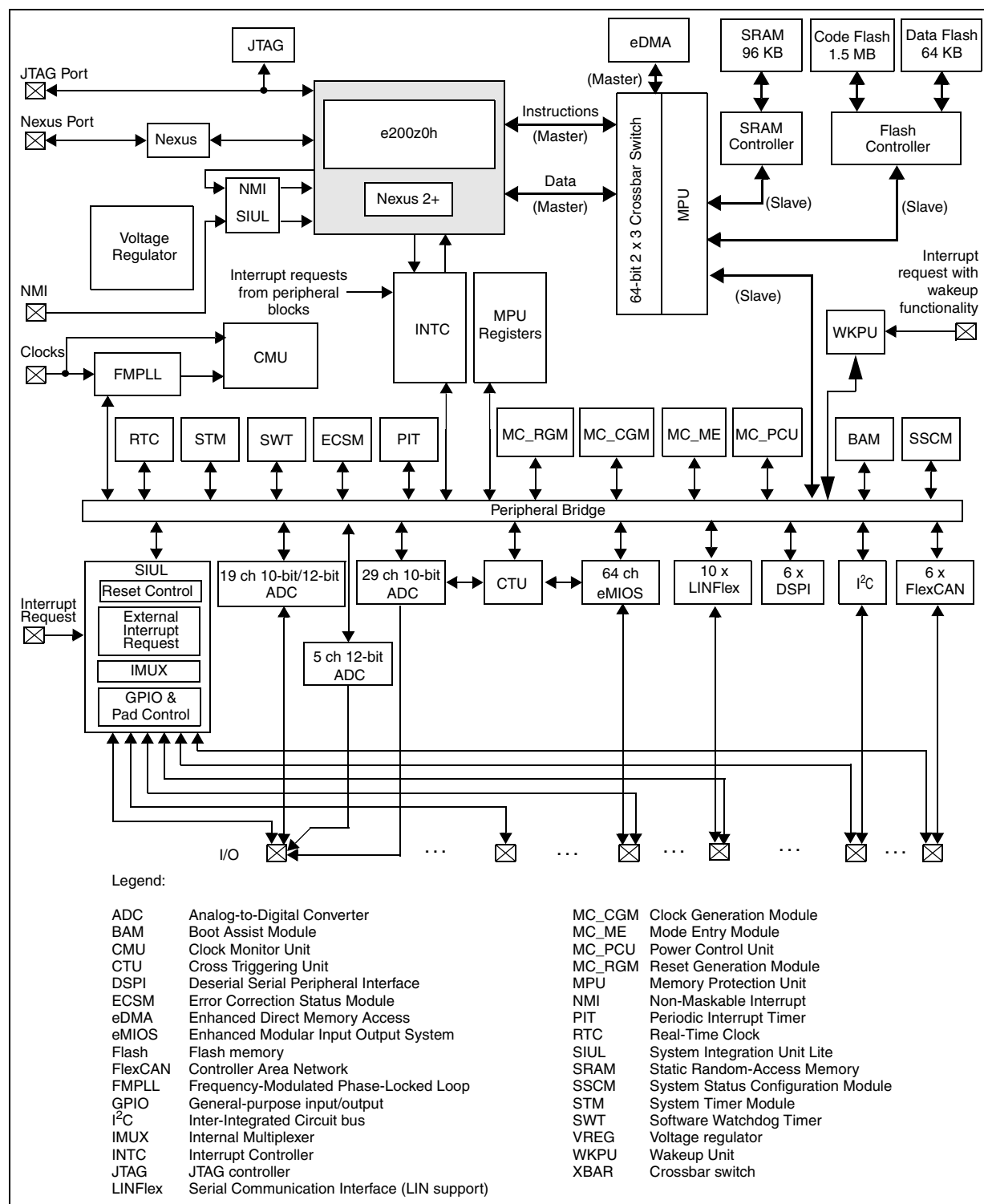


Figure 1. MPC5607B block diagram

3.7 Functional port pins

The functional port pins are listed in [Table 5](#).

Table 5. Functional port pin descriptions

Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration ³	Pin number			
								100 LQFP	144 LQFP	176 LQFP	208 MAP BGA ⁴
Port A											
PA[0]	PCR[0]	AF0 AF1 AF2 AF3 —	GPIO[0] E0UC[0] CLKOUT E0UC[13] WKPU[19] ⁵	SIUL eMIOS_0 MC_CGM eMIOS_0 WKPU	I/O I/O O I/O I	M	Tristate	12	16	24	G4
PA[1]	PCR[1]	AF0 AF1 AF2 AF3 —	GPIO[1] E0UC[1] NMI ⁶ — WKPU[2] ⁵	SIUL eMIOS_0 WKPU — WKPU	I/O I/O I — I	S	Tristate	7	11	19	F3
PA[2]	PCR[2]	AF0 AF1 AF2 AF3 —	GPIO[2] E0UC[2] — MA[2] WKPU[3] ⁵	SIUL eMIOS_0 — ADC_0 WKPU	I/O I/O — O I	S	Tristate	5	9	17	F2
PA[3]	PCR[3]	AF0 AF1 AF2 AF3 — —	GPIO[3] E0UC[3] LIN5TX CS4_1 EIRQ[0] ADC1_S[0]	SIUL eMIOS_0 LINFlex_5 DSPI_1 SIUL ADC_1	I/O I/O O O I I	J	Tristate	68	90	114	K15
PA[4]	PCR[4]	AF0 AF1 AF2 AF3 — —	GPIO[4] E0UC[4] — CS0_1 LIN5RX WKPU[9] ⁵	SIUL eMIOS_0 — DSPI_1 LINFlex_5 WKPU	I/O I/O — I/O I I	S	Tristate	29	43	51	N6
PA[5]	PCR[5]	AF0 AF1 AF2 AF3	GPIO[5] E0UC[5] LIN4TX —	SIUL eMIOS_0 LINFlex_4 —	I/O I/O O —	M	Tristate	79	118	146	C11
PA[6]	PCR[6]	AF0 AF1 AF2 AF3 — —	GPIO[6] E0UC[6] — CS1_1 EIRQ[1] LIN4RX	SIUL eMIOS_0 — DSPI_1 SIUL LINFlex_4	I/O I/O — O I I	S	Tristate	80	119	147	D11

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration ³	Pin number			
								100 LQFP	144 LQFP	176 LQFP	208 MAP BGA ⁴
PC[11]	PCR[43]	AF0 AF1 AF2 AF3 — — —	GPIO[43] — — MA[2] WKPU[5] ⁵ CAN1RX CAN4RX	SIUL — — ADC_0 WKPU FlexCAN_1 FlexCAN_4	I/O — — O I I I	S	Tristate	21	27	35	M4
PC[12]	PCR[44]	AF0 AF1 AF2 AF3 — —	GPIO[44] E0UC[12] — — EIRQ[19] SIN_2	SIUL eMIOS_0 — — SIUL DSPI_2	I/O I/O — — I I	M	Tristate	97	141	173	B4
PC[13]	PCR[45]	AF0 AF1 AF2 AF3	GPIO[45] E0UC[13] SOUT_2 —	SIUL eMIOS_0 DSPI_2 —	I/O I/O O —	S	Tristate	98	142	174	A2
PC[14]	PCR[46]	AF0 AF1 AF2 AF3 —	GPIO[46] E0UC[14] SCK_2 — EIRQ[8]	SIUL eMIOS_0 DSPI_2 — SIUL	I/O I/O I/O — I	S	Tristate	3	3	3	C1
PC[15]	PCR[47]	AF0 AF1 AF2 AF3 —	GPIO[47] E0UC[15] CS0_2 — EIRQ[20]	SIUL eMIOS_0 DSPI_2 — SIUL	I/O I/O I/O — I	M	Tristate	4	4	4	D3
Port D											
PD[0]	PCR[48]	AF0 AF1 AF2 AF3 — — —	GPIO[48] — — — WKPU[27] ⁵ ADC0_P[4] ADC1_P[4]	SIUL — — — WKPU ADC_0 ADC_1	I — — — I I I	I	Tristate	41	63	77	P12
PD[1]	PCR[49]	AF0 AF1 AF2 AF3 — — —	GPIO[49] — — — WKPU[28] ⁵ ADC0_P[5] ADC1_P[5]	SIUL — — — WKPU ADC_0 ADC_1	I — — — I I I	I	Tristate	42	64	78	T12

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration ³	Pin number			
								100 LQFP	144 LQFP	176 LQFP	208 MAP BGA ⁴
PD[9]	PCR[57]	AF0 AF1 AF2 AF3 — —	GPIO[57] — — — ADC0_P[13] ADC1_P[13]	SIUL — — — ADC_0 ADC_1	I — — — I I	I	Tristate	56	78	94	N15
PD[10]	PCR[58]	AF0 AF1 AF2 AF3 — —	GPIO[58] — — — ADC0_P[14] ADC1_P[14]	SIUL — — — ADC_0 ADC_1	I — — — I I	I	Tristate	57	79	95	N14
PD[11]	PCR[59]	AF0 AF1 AF2 AF3 — —	GPIO[59] — — — ADC0_P[15] ADC1_P[15]	SIUL — — — ADC_0 ADC_1	I — — — I I	I	Tristate	58	80	96	N16
PD[12]	PCR[60]	AF0 AF1 AF2 AF3 —	GPIO[60] CS5_0 E0UC[24] — ADC0_S[4]	SIUL DSPI_0 eMIOS_0 — ADC_0	I/O O I/O — I	J	Tristate	—	—	100	M15
PD[13]	PCR[61]	AF0 AF1 AF2 AF3 —	GPIO[61] CS0_1 E0UC[25] — ADC0_S[5]	SIUL DSPI_1 eMIOS_0 — ADC_0	I/O I/O I/O — I	J	Tristate	62	84	102	M14
PD[14]	PCR[62]	AF0 AF1 AF2 AF3 —	GPIO[62] CS1_1 E0UC[26] — ADC0_S[6]	SIUL DSPI_1 eMIOS_0 — ADC_0	I/O O I/O — I	J	Tristate	64	86	104	L15
PD[15]	PCR[63]	AF0 AF1 AF2 AF3 —	GPIO[63] CS2_1 E0UC[27] — ADC0_S[7]	SIUL DSPI_1 eMIOS_0 — ADC_0	I/O O I/O — I	J	Tristate	66	88	106	L14
Port E											

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration ³	Pin number			
								100 LQFP	144 LQFP	176 LQFP	208 MAP BGA ⁴
PF[0]	PCR[80]	AF0 AF1 AF2 AF3 —	GPIO[80] E0UC[10] CS3_1 — ADC0_S[8]	SIUL eMIOS_0 DSPI_1 — ADC_0	I/O I/O O — I	J	Tristate	—	55	63	N10
PF[1]	PCR[81]	AF0 AF1 AF2 AF3 —	GPIO[81] E0UC[11] CS4_1 — ADC0_S[9]	SIUL eMIOS_0 DSPI_1 — ADC_0	I/O I/O O — I	J	Tristate	—	56	64	P10
PF[2]	PCR[82]	AF0 AF1 AF2 AF3 —	GPIO[82] E0UC[12] CS0_2 — ADC0_S[10]	SIUL eMIOS_0 DSPI_2 — ADC_0	I/O I/O I/O — I	J	Tristate	—	57	65	T10
PF[3]	PCR[83]	AF0 AF1 AF2 AF3 —	GPIO[83] E0UC[13] CS1_2 — ADC0_S[11]	SIUL eMIOS_0 DSPI_2 — ADC_0	I/O I/O O — I	J	Tristate	—	58	66	R10
PF[4]	PCR[84]	AF0 AF1 AF2 AF3 —	GPIO[84] E0UC[14] CS2_2 — ADC0_S[12]	SIUL eMIOS_0 DSPI_2 — ADC_0	I/O I/O O — I	J	Tristate	—	59	67	N11
PF[5]	PCR[85]	AF0 AF1 AF2 AF3 —	GPIO[85] E0UC[22] CS3_2 — ADC0_S[13]	SIUL eMIOS_0 DSPI_2 — ADC_0	I/O I/O O — I	J	Tristate	—	60	68	P11
PF[6]	PCR[86]	AF0 AF1 AF2 AF3 —	GPIO[86] E0UC[23] CS1_1 — ADC0_S[14]	SIUL eMIOS_0 DSPI_1 — ADC_0	I/O I/O O — I	J	Tristate	—	61	69	T11
PF[7]	PCR[87]	AF0 AF1 AF2 AF3 —	GPIO[87] — CS2_1 — ADC0_S[15]	SIUL — DSPI_1 — ADC_0	I/O — O — I	J	Tristate	—	62	70	R11

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function ¹	Function	Peripheral	I/O direction ²	Pad type	RESET configuration ³	Pin number			
								100 LQFP	144 LQFP	176 LQFP	208 MAP BGA ⁴
PI[4]	PCR[132]	AF0 AF1 AF2 AF3	GPIO[132] E1UC[28] SOUT_4 —	SIUL eMIOS_1 DSPI_4 —	I/O I/O O —	S	Tristate	—	—	143	A12
PI[5]	PCR[133]	AF0 AF1 AF2 AF3	GPIO[133] E1UC[29] SCK_4 —	SIUL eMIOS_1 DSPI_4 —	I/O I/O I/O —	S	Tristate	—	—	142	C12
PI[6]	PCR[134]	AF0 AF1 AF2 AF3	GPIO[134] E1UC[30] CS0_4 —	SIUL eMIOS_1 DSPI_4 —	I/O I/O I/O —	S	Tristate	—	—	11	D2
PI[7]	PCR[135]	AF0 AF1 AF2 AF3	GPIO[135] E1UC[31] CS1_4 —	SIUL eMIOS_1 DSPI_4 —	I/O I/O O —	S	Tristate	—	—	12	D3
PI[8]	PCR[136]	AF0 AF1 AF2 AF3 —	GPIO[136] — — — ADC0_S[16]	SIUL — — — ADC_0	I/O — — — I	J	Tristate	—	—	108	J13
PI[9]	PCR[137]	AF0 AF1 AF2 AF3 —	GPIO[137] — — — ADC0_S[17]	SIUL — — — ADC_0	I/O — — — I	J	Tristate	—	—	109	J14
PI[10]	PCR[138]	AF0 AF1 AF2 AF3 —	GPIO[138] — — — ADC0_S[18]	SIUL — — — ADC_0	I/O — — — I	J	Tristate	—	—	110	J15
PI[11]	PCR[139]	AF0 AF1 AF2 AF3 — —	GPIO[139] — — — ADC0_S[19] SIN_3	SIUL — — — ADC_0 DSPI_3	I/O — — — I I	J	Tristate	—	—	111	J16
PI[12]	PCR[140]	AF0 AF1 AF2 AF3 —	GPIO[140] CS0_3 — — ADC0_S[20]	SIUL DSPI_3 — — ADC_0	I/O I/O — — I	J	Tristate	—	—	112	G14

Table 8. PAD3V5V field description¹

Value ²	Description
0	High voltage supply is 5.0 V
1	High voltage supply is 3.3 V

¹ See the device reference manual for more information on the NVUSRO register.

² Default manufacturing value is '1'. Value can be programmed by customer in Shadow Flash.

4.2.2 NVUSRO[OSCILLATOR_MARGIN] field description

The fast external crystal oscillator consumption is dependent on the OSCILLATOR_MARGIN bit value. Table 9 shows how NVUSRO[OSCILLATOR_MARGIN] controls the device configuration.

Table 9. OSCILLATOR_MARGIN field description¹

Value ²	Description
0	Low consumption configuration (4 MHz/8 MHz)
1	High margin configuration (4 MHz/16 MHz)

¹ See the device reference manual for more information on the NVUSRO register.

² Default manufacturing value is '1'. Value can be programmed by customer in Shadow Flash.

4.2.3 NVUSRO[WATCHDOG_EN] field description

The watchdog enable/disable configuration after reset is dependent on the WATCHDOG_EN bit value. Table 10 shows how NVUSRO[WATCHDOG_EN] controls the device configuration.

Table 10. WATCHDOG_EN field description

Value ¹	Description
0	Disable after reset
1	Enable after reset

¹ Default manufacturing value is '1'. Value can be programmed by customer in Shadow Flash.

4.3 Absolute maximum ratings

Table 11. Absolute maximum ratings

Symbol		Parameter	Conditions	Value		Unit
				Min	Max	
V _{SS}	SR	Digital ground on VSS_HV pins	—	0	0	V
V _{DD}	SR	Voltage on VDD_HV pins with respect to ground (V _{SS})	—	−0.3	6.0	V
V _{SS_LV}	SR	Voltage on VSS_LV (low voltage digital supply) pins with respect to ground (V _{SS})	—	V _{SS} − 0.1	V _{SS} + 0.1	V
V _{DD_BV}	SR	Voltage on VDD_BV (regulator supply) pin with respect to ground (V _{SS})	—	−0.3	6.0	V
			Relative to V _{DD}	−0.3	V _{DD} + 0.3	

Table 12. Recommended operating conditions (3.3 V) (continued)

Symbol		Parameter	Conditions	Value		Unit
				Min	Max	
V_{SS_ADC}	SR	Voltage on VSS_HV_ADC0, VSS_HV_ADC1 (ADC reference) pin with respect to ground (V_{SS})	—	$V_{SS} - 0.1$	$V_{SS} + 0.1$	V
$V_{DD_ADC}^4$	SR	Voltage on VDD_HV_ADC0, VDD_HV_ADC1 (ADC reference) with respect to ground (V_{SS})	—	3.0 ⁵	3.6	V
			Relative to V_{DD}	$V_{DD} - 0.1$	$V_{DD} + 0.1$	
V_{IN}	SR	Voltage on any GPIO pin with respect to ground (V_{SS})	—	$V_{SS} - 0.1$	—	V
			Relative to V_{DD}	—	$V_{DD} + 0.1$	
I_{INPAD}	SR	Injected input current on any pin during overload condition	—	–5	5	mA
I_{INJSUM}	SR	Absolute sum of all injected input currents during overload condition	—	–50	50	
TV_{DD}	SR	V_{DD} slope to ensure correct power up ⁶	—	—	0.25	V/ μ s
T_A C-Grade Part	SR	Ambient temperature under bias	$f_{CPU} < 64 \text{ MHz}^7$	–40	85	°C
T_J C-Grade Part	SR	Junction temperature under bias	—	–40	110	
T_A V-Grade Part	SR	Ambient temperature under bias	$f_{CPU} < 64 \text{ MHz}^7$	–40	105	
T_J V-Grade Part	SR	Junction temperature under bias	—	–40	130	
T_A M-Grade Part	SR	Ambient temperature under bias	$f_{CPU} < 64 \text{ MHz}^7$	–40	125	
T_J M-Grade Part	SR	Junction temperature under bias	—	–40	150	

¹ 100 nF capacitance needs to be provided between each V_{DD}/V_{SS} pair.

² 330 nF capacitance needs to be provided between each V_{DD_LV}/V_{SS_LV} supply pair.

³ 470 nF capacitance needs to be provided between V_{DD_BV} and the nearest V_{SS_LV} (higher value may be needed depending on external regulator characteristics). Supply ramp slope on V_{DD_BV} should always be faster or equal to slope of V_{DD_HV} . Otherwise, device may enter regulator bypass mode if slope on V_{DD_BV} is slower.

⁴ 100 nF capacitance needs to be provided between V_{DD_ADC}/V_{SS_ADC} pair.

⁵ Full electrical specification cannot be guaranteed when voltage drops below 3.0 V. In particular, ADC electrical characteristics and I/Os DC electrical specification may not be guaranteed. When voltage drops below V_{LVDHVL} , device is reset.

⁶ Guaranteed by device validation

⁷ This frequency includes the 4% frequency modulation guardband.

Table 13. Recommended operating conditions (5.0 V)

Symbol		Parameter	Conditions	Value		Unit
				Min	Max	
V_{SS}	SR	Digital ground on VSS_HV pins	—	0	0	V
V_{DD}^1	SR	Voltage on VDD_HV pins with respect to ground (V_{SS})	—	4.5	5.5	V
			Voltage drop ²	3.0	5.5	
$V_{SS_LV}^3$	SR	Voltage on VSS_LV (low voltage digital supply) pins with respect to ground (V_{SS})	—	$V_{SS} - 0.1$	$V_{SS} + 0.1$	V

² The configuration PAD3V5 = 1 when $V_{DD} = 5\text{ V}$ is only a transient configuration during power-up. All pads but RESET and Nexus output (MDOx, EVTO, MCKO) are configured in input or in high impedance state.

4.6.4 Output pin transition times

Table 20. Output pin transition times

Symbol		C	Parameter	Conditions ¹		Value			Unit
						Min	Typ	Max	
T _{tr}	CC	D	Output transition time output pin ² SLOW configuration	C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	50	ns
		T		C _L = 50 pF		—	—	100	
		D		C _L = 100 pF		—	—	125	
		D		C _L = 25 pF	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	50	
		T		C _L = 50 pF		—	—	100	
		D		C _L = 100 pF		—	—	125	
		T _{tr}		CC	D	Output transition time output pin ² MEDIUM configuration	C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0 SIUL.PCRx.SRC = 1	
T	C _L = 50 pF		—		—		20		
D	C _L = 100 pF		—		—		40		
D	C _L = 25 pF		V _{DD} = 3.3 V ± 10%, PAD3V5V = 1 SIUL.PCRx.SRC = 1		—		—	12	
T	C _L = 50 pF				—		—	25	
D	C _L = 100 pF				—		—	40	
T _{tr}	CC		D		Output transition time output pin ² FAST configuration		C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—
		C _L = 50 pF	—	—		6			
		C _L = 100 pF	—	—		12			
		C _L = 25 pF	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—		—	4		
		C _L = 50 pF		—		—	7		
		C _L = 100 pF		—		—	12		

¹ $V_{DD} = 3.3\text{ V} \pm 10\% / 5.0\text{ V} \pm 10\%$, $T_A = -40$ to $125\text{ }^\circ\text{C}$, unless otherwise specified

² C_L includes device and package capacitances ($C_{PKG} < 5\text{ pF}$).

4.6.5 I/O pad current specification

The I/O pads are distributed across the I/O supply segment. Each I/O supply segment is associated to a V_{DD}/V_{SS} supply pair as described in [Table 21](#).

[Table 22](#) provides I/O consumption figures.

In order to ensure device reliability, the average current of the I/O on a single segment should remain below the I_{AVGSEG} maximum value.

4.7 $\overline{\text{RESET}}$ electrical characteristics

The device implements a dedicated bidirectional $\overline{\text{RESET}}$ pin.

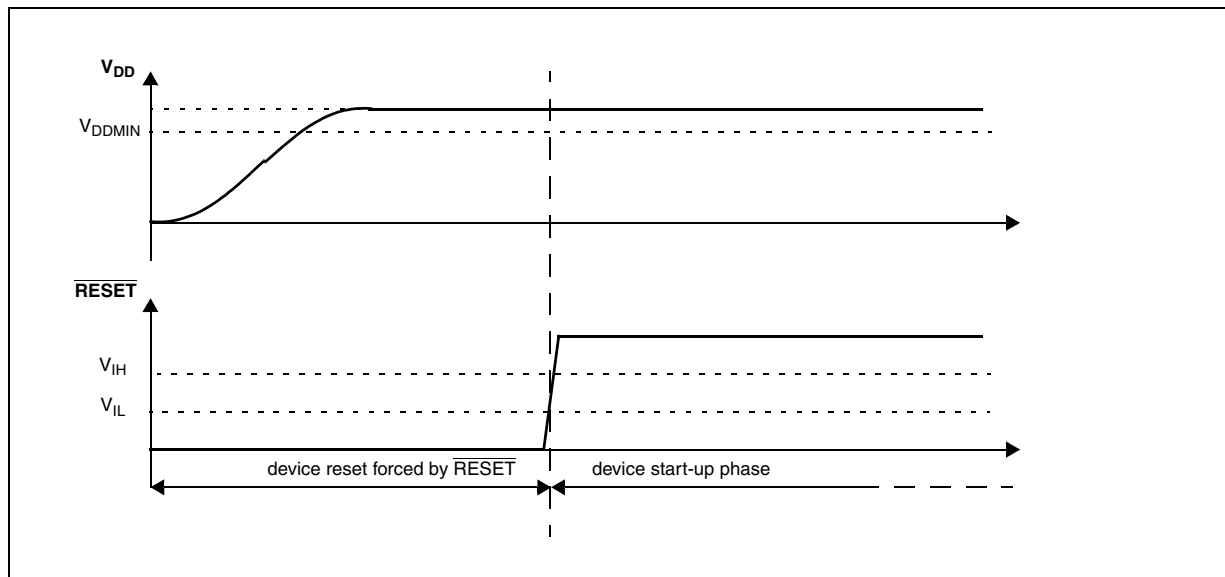


Figure 7. Start-up reset requirements

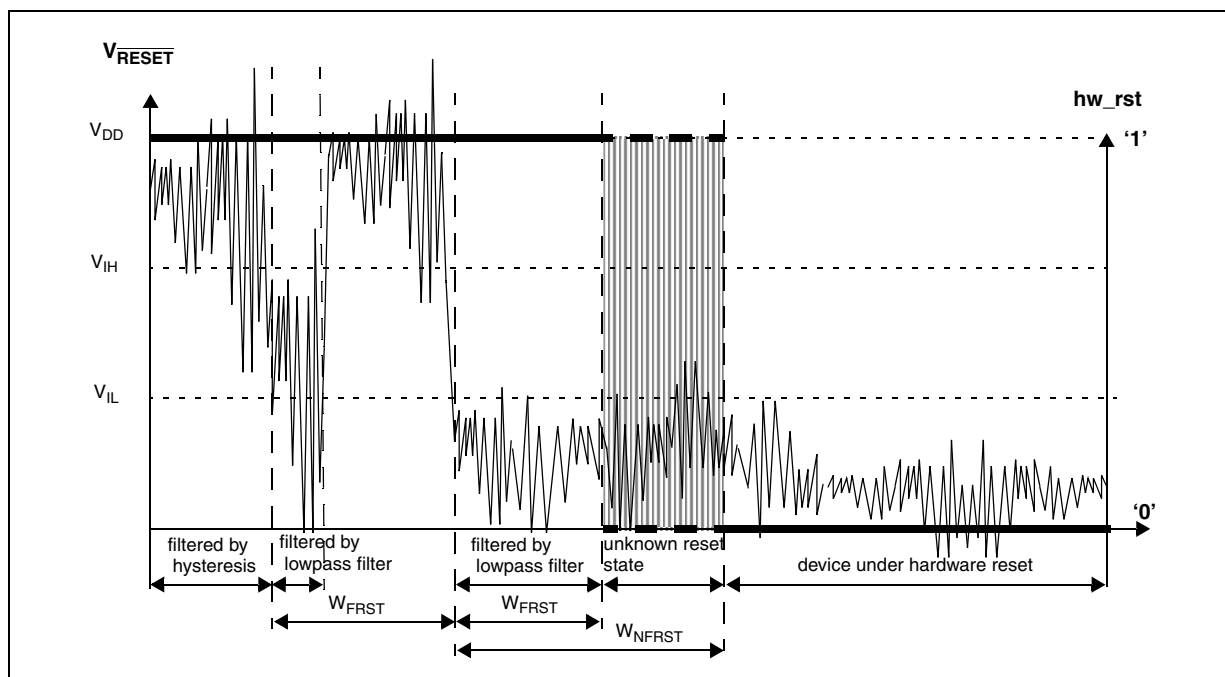


Figure 8. Noise filtering on reset signal

Table 41. Fast internal RC oscillator (16 MHz) electrical characteristics (continued)

Symbol	C	Parameter	Conditions ¹	Value			Unit	
				Min	Typ	Max		
I _{FIRCSTOP}	CC	T Fast internal RC oscillator high frequency and system clock current in stop mode	T _A = 25 °C	sysclk = off	—	500	—	μA
				sysclk = 2 MHz	—	600	—	
				sysclk = 4 MHz	—	700	—	
				sysclk = 8 MHz	—	900	—	
				sysclk = 16 MHz	—	1250	—	
t _{FIRCSU}	CC	C Fast internal RC oscillator start-up time	V _{DD} = 5.0 V ± 10%		—	1.1	2.0	μs
Δ _{FIRCPRE}	CC	C Fast internal RC oscillator precision after software trimming of f _{FIRC}	T _A = 25 °C		−1	—	1	%
Δ _{FIRCTRM}	CC	C Fast internal RC oscillator trimming step	T _A = 25 °C		—	1.6		%
Δ _{FIRCVAR}	CC	C Fast internal RC oscillator variation over temperature and supply with respect to f _{FIRC} at T _A = 25 °C in high-frequency configuration	—		−5	—	5	%

¹ V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C, unless otherwise specified

² This does not include consumption linked to clock tree toggling and peripherals consumption when RC oscillator is ON.

4.16 Slow internal RC oscillator (128 kHz) electrical characteristics

The device provides a 128 kHz low power internal RC oscillator. This can be used as the reference clock for the RTC module.

Table 42. Slow internal RC oscillator (128 kHz) electrical characteristics

Symbol		C	Parameter	Conditions ¹	Value			Unit
					Min	Typ	Max	
f _{SIRC}	CC	P	Slow internal RC oscillator low frequency	T _A = 25 °C, trimmed	—	128	—	kHz
	SR	—		—	100	—	150	
I _{SIRC} ² ,	CC	C	Slow internal RC oscillator low frequency current	T _A = 25 °C, trimmed	—	—	5	μA
t _{SIRCSU}	CC	P	Slow internal RC oscillator start-up time	T _A = 25 °C, V _{DD} = 5.0 V ± 10%	—	8	12	μs
Δ _{SIRCPRE}	CC	C	Slow internal RC oscillator precision after software trimming of f _{SIRC}	T _A = 25 °C	–2	—	2	%
Δ _{SIRCTRM}	CC	C	Slow internal RC oscillator trimming step	—	—	2.7	—	

Table 42. Slow internal RC oscillator (128 kHz) electrical characteristics (continued)

Symbol		C	Parameter	Conditions ¹	Value			Unit
					Min	Typ	Max	
$\Delta_{\text{SIRC}}\text{VAR}$	CC	C	Slow internal RC oscillator variation in temperature and supply with respect to f_{SIRC} at $T_A = 55\text{ }^{\circ}\text{C}$ in high frequency configuration	High frequency configuration	−10	—	10	%

¹ $V_{\text{DD}} = 3.3\text{ V} \pm 10\% / 5.0\text{ V} \pm 10\%$, $T_A = -40$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified

² This does not include consumption linked to clock tree toggling and peripherals consumption when RC oscillator is ON.

4.17 ADC electrical characteristics

4.17.1 Introduction

The device provides two Successive Approximation Register (SAR) analog-to-digital converters (10-bit and 12-bit).

Table 44. ADC_0 conversion characteristics (10-bit ADC_0) (continued)

Symbol		C	Parameter	Conditions ¹		Value			Unit
						Min	Typ	Max	
R _{SW1}	CC	D	Internal resistance of analog source	—		—	—	3	kΩ
R _{SW2}	CC	D	Internal resistance of analog source	—		—	—	2	kΩ
R _{AD}	CC	D	Internal resistance of analog source	—		—	—	2	kΩ
I _{INJ}	SR	—	Input current Injection	Current injection on one ADC_0 input, different from the converted one	V _{DD} = 3.3 V ± 10%	−5	—	5	mA
					V _{DD} = 5.0 V ± 10%	−5	—	5	
INL	CC	T	Absolute integral nonlinearity	No overload		—	0.5	1.5	LSB
DNL	CC	T	Absolute differential nonlinearity	No overload		—	0.5	1.0	LSB
E _O	CC	T	Absolute offset error	—		—	0.5	—	LSB
E _G	CC	T	Absolute gain error	—		—	0.6	—	LSB
TUEP	CC	P	Total unadjusted error ⁷ for precise channels, input only pins	Without current injection		−2	0.6	2	LSB
		With current injection		−3	—	3			
TUEX	CC	T	Total unadjusted error ⁷ for extended channel	Without current injection		−3	1	3	LSB
		With current injection		−4		4			

¹ V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = -40 to 125 °C, unless otherwise specified.

² Analog and digital V_{SS} **must** be common (to be tied together externally).

³ V_{AINx} may exceed V_{SS_ADC0} and V_{DD_ADC0} limits, remaining on absolute maximum ratings, but the results of the conversion will be clamped respectively to 0x000 or 0x3FF.

⁴ Duty cycle is ensured by using system clock without prescaling. When ADCLKSEL = 0, the duty cycle is ensured by internal divider by 2.

⁵ During the sampling time the input capacitance C_S can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within t_{ADC0_S}. After the end of the sampling time t_{ADC0_S}, changes of the analog input voltage have no effect on the conversion result. Values for the sampling clock t_{ADC0_S} depend on programming.

⁶ This parameter does not include the sampling time t_{ADC0_S}, but only the time for determining the digital result and the time to load the result's register with the conversion result.

⁷ Total Unadjusted Error: The maximum error that occurs without adjusting Offset and Gain errors. This error is a combination of Offset, Gain and Integral Linearity errors.

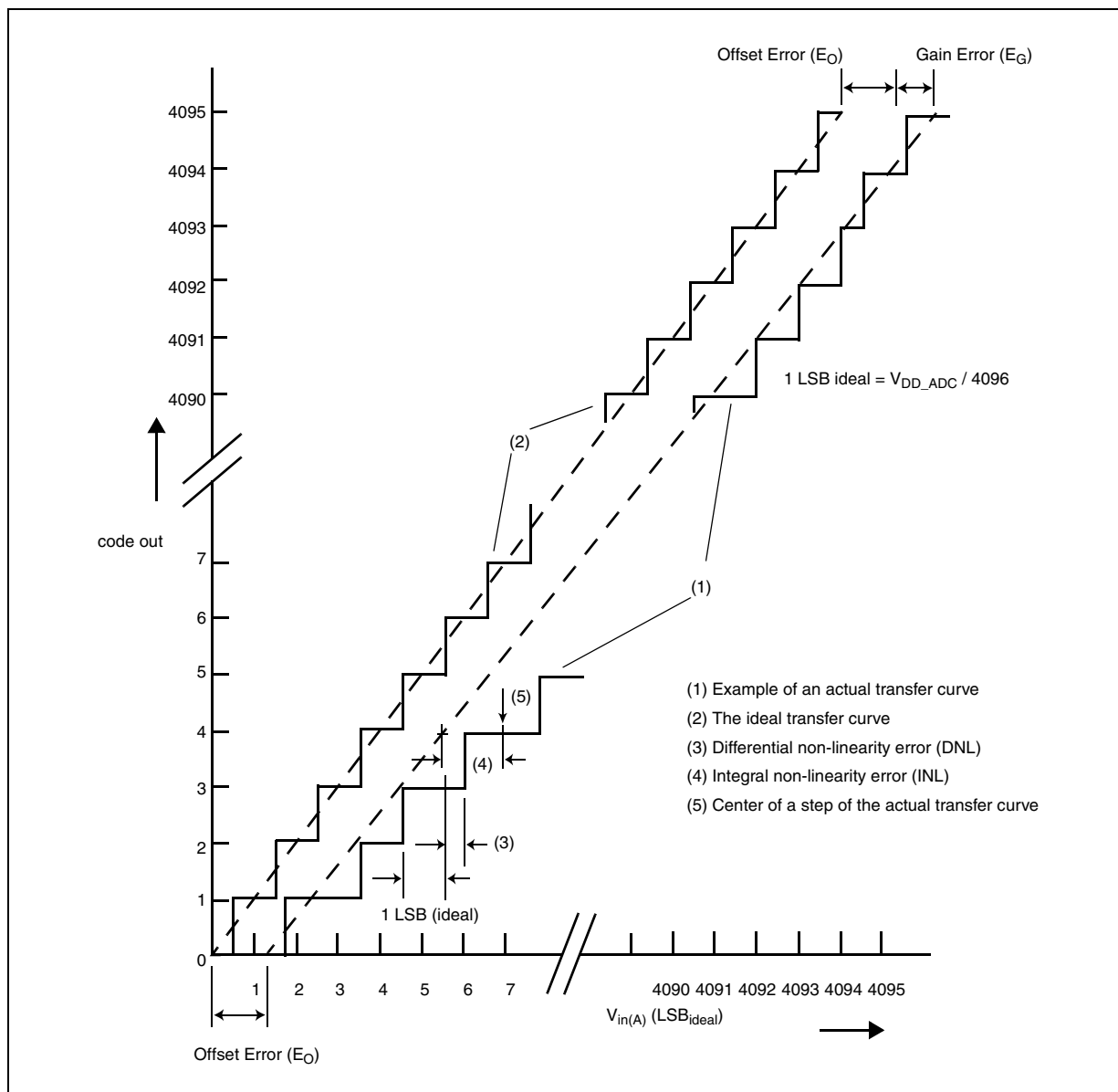


Figure 21. ADC_1 characteristic and error definitions

Table 45. ADC_1 conversion characteristics (12-bit ADC_1)

Symbol	C	Parameter	Conditions ¹	Value			Unit
				Min	Typ	Max	
V_{SS_ADC1}	SR	—	—	—0.1	—	0.1	V
V_{DD_ADC1}	SR	—	—	$V_{DD} - 0.1$	—	$V_{DD} + 0.1$	V

Table 45. ADC_1 conversion characteristics (12-bit ADC_1) (continued)

Symbol		C	Parameter	Conditions ¹		Value			Unit
						Min	Typ	Max	
I _{INJ}	SR	—	Input current Injection	Current injection on one ADC_1 input, different from the converted one	V _{DD} = 3.3 V ± 10%	−5	—	5	mA
					V _{DD} = 5.0 V ± 10%	−5	—	5	
INLP	CC	T	Absolute integral nonlinearity – Precise channels	No overload		—	1	3	LSB
INLX	CC	T	Absolute integral nonlinearity – Extended channels	No overload		—	1.5	5	LSB
DNL	CC	T	Absolute differential nonlinearity	No overload		—	0.5	1	LSB
E _O	CC	T	Absolute offset error	—		—	2	—	LSB
E _G	CC	T	Absolute gain error	—		—	2	—	LSB
TUEP ⁷	CC	P	Total unadjusted error for precise channels, input only pins	Without current injection		−6	—	6	LSB
		With current injection		−8	—	8			
TUEX ⁷	CC	T	Total unadjusted error for extended channel	Without current injection		−10	—	10	LSB
		With current injection		−12	—	12			

¹ V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C, unless otherwise specified

² Analog and digital V_{SS} **must** be common (to be tied together externally).

³ V_{AINx} may exceed V_{SS_ADC1} and V_{DD_ADC1} limits, remaining on absolute maximum ratings, but the results of the conversion will be clamped respectively to 0x000 or 0xFF.

⁴ During the sampling time the input capacitance C_S can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within t_{ADC1_S}. After the end of the sampling time t_{ADC1_S}, changes of the analog input voltage have no effect on the conversion result. Values for the sampling clock t_{ADC1_S} depend on programming.

⁵ This parameter does not include the sampling time t_{ADC1_S}, but only the time for determining the digital result and the time to load the result's register with the conversion result.

⁶ Duty cycle is ensured by using system clock without prescaling. When ADCLKSEL = 0, the duty cycle is ensured by internal divider by 2.

⁷ Total Unadjusted Error: The maximum error that occurs without adjusting Offset and Gain errors. This error is a combination of Offset, Gain and Integral Linearity errors.

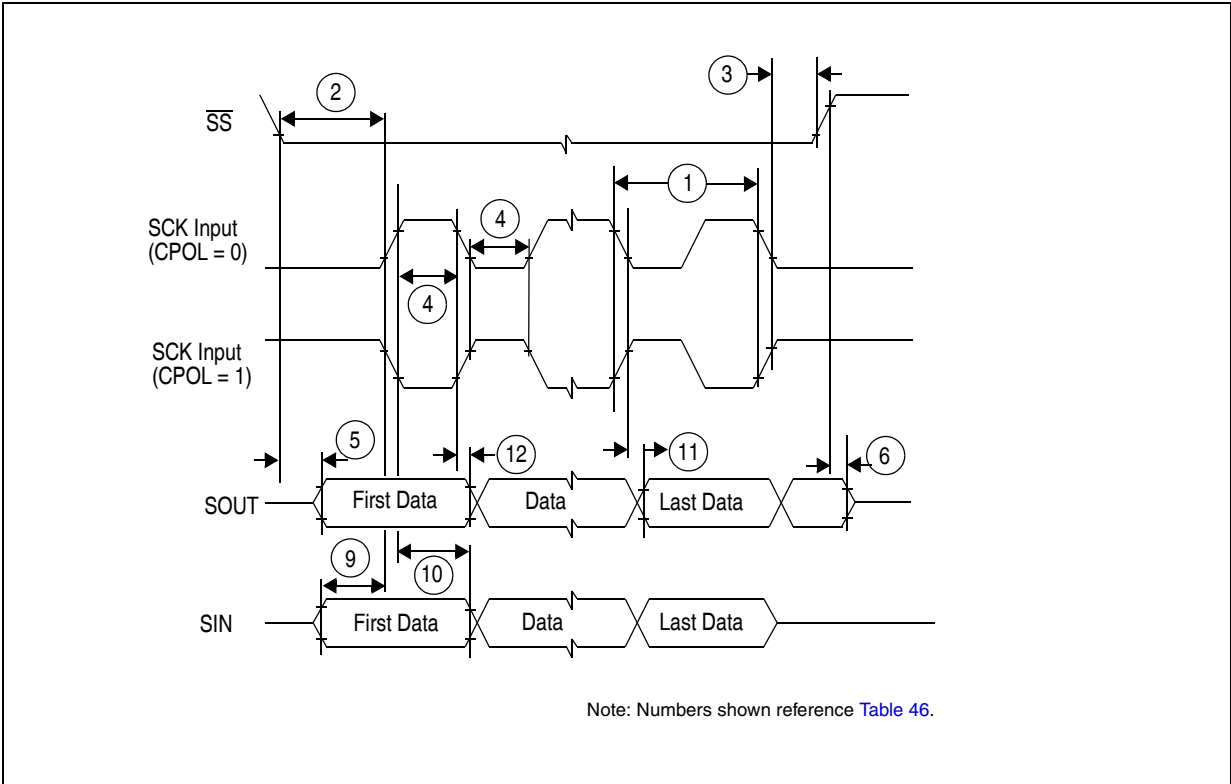


Figure 24. DSPI classic SPI timing — slave, CPHA = 0

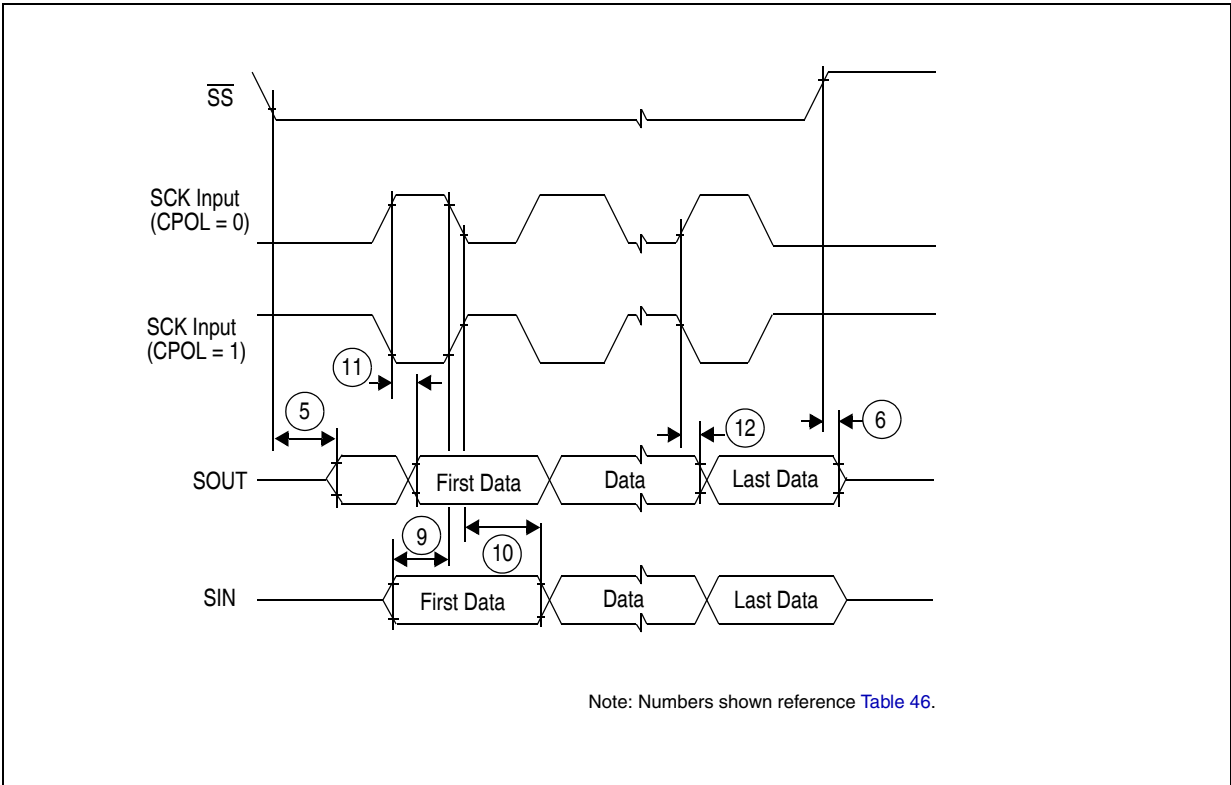


Figure 25. DSPI classic SPI timing — slave, CPHA = 1

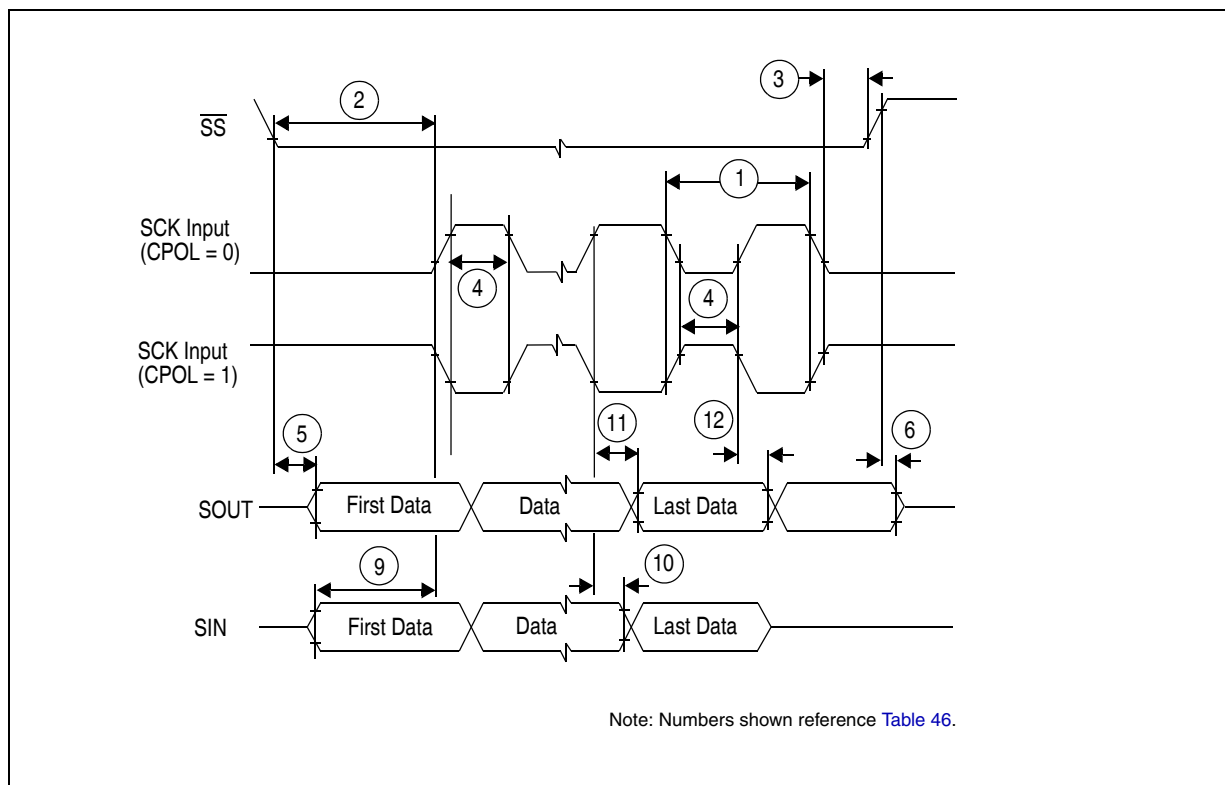


Figure 28. DSPI modified transfer format timing — slave, CPHA = 0

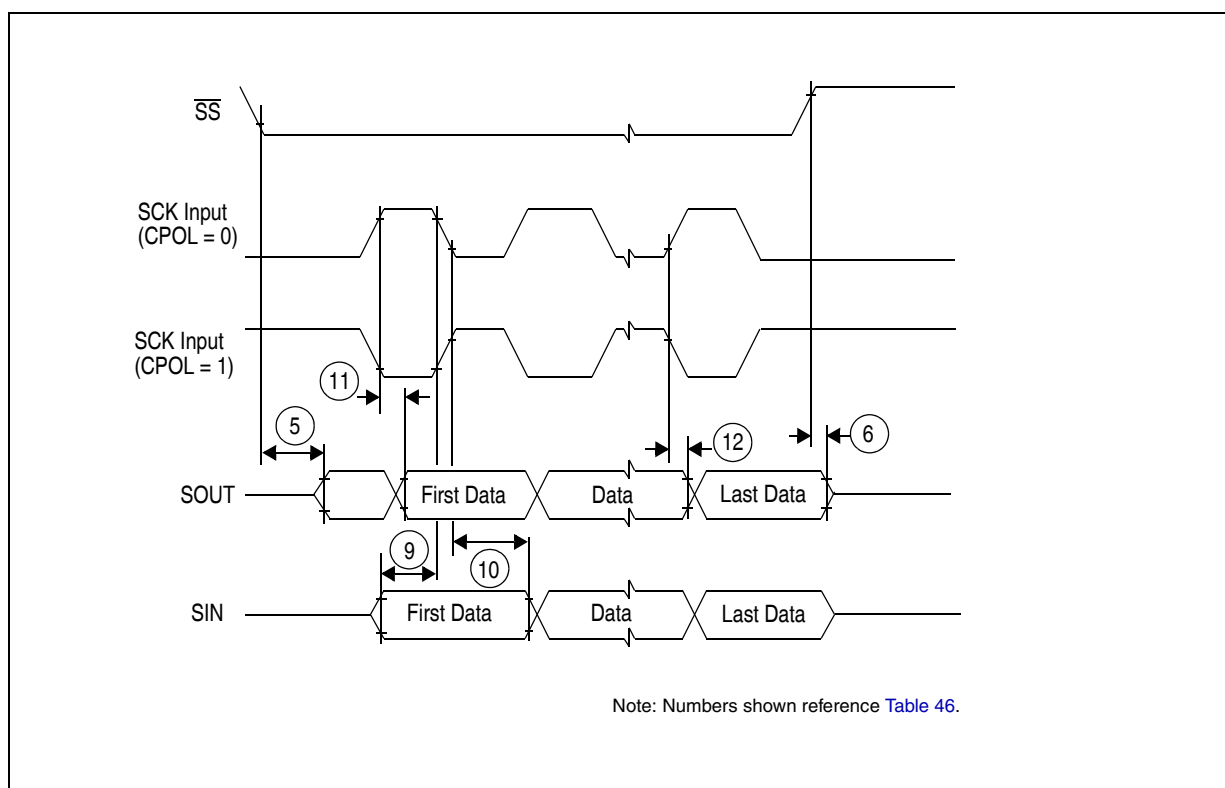


Figure 29. DSPI modified transfer format timing — slave, CPHA = 1

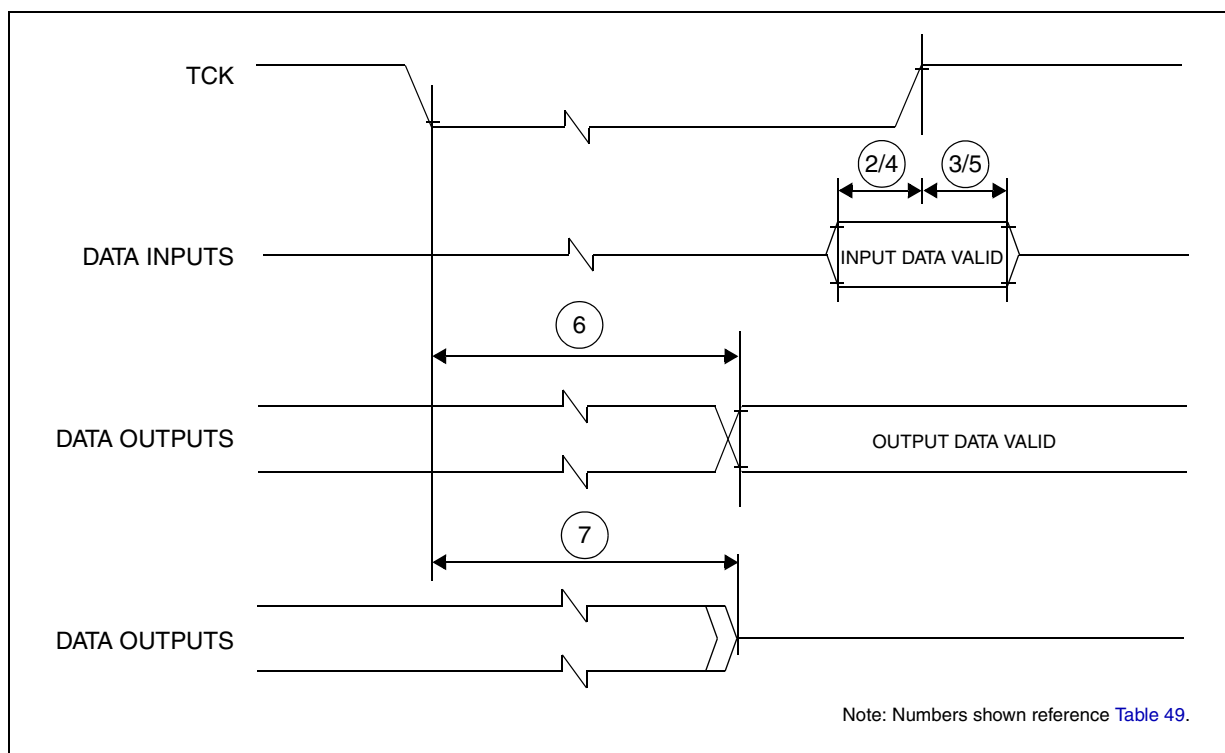


Figure 32. Timing diagram — JTAG boundary scan

